

FRONT-END

MOS-FET

IGBT

DIODE

SEMICONDUCTOR TEST SYSTEM / QG TESTER 半導体テストシステム / QG テスター

CWT2020Z/QGR520Z

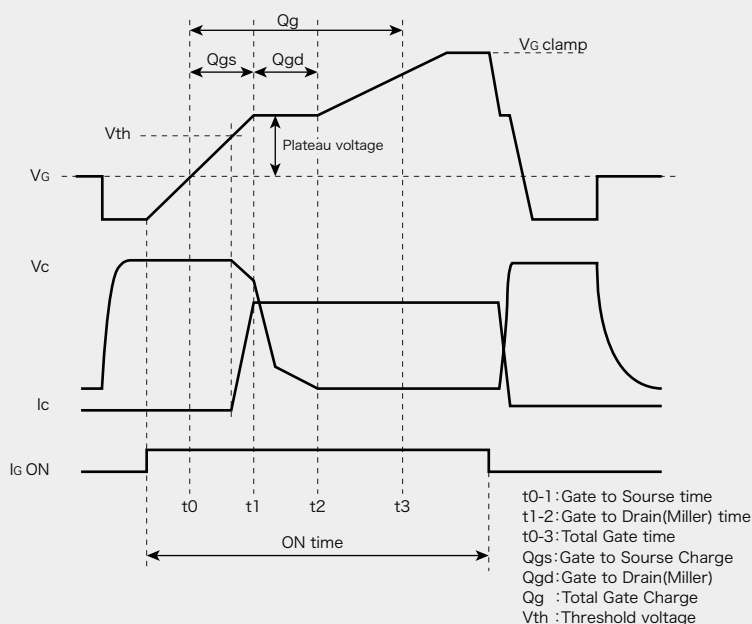
2000V
200A

● This system has been developed for wafer measurement and can measure DC and QG measurements (R load) at once. The measuring section is a sliding overhead type with a mechanism to minimize the measuring distance. The oscilloscope waveform is analysed and displayed on the software.

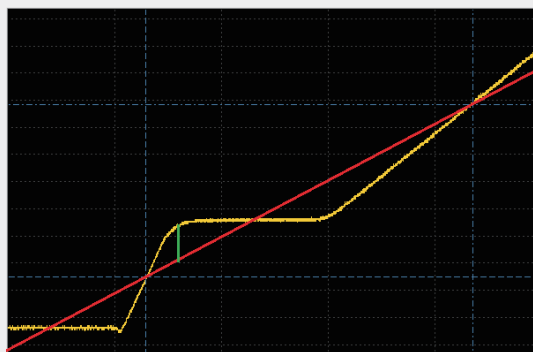
● 本器はウェハ測定用として開発されたシステムで、DC 測定と QG 測定 (R 負荷) を一度に測定できます。測定部はスライド式のオーバーヘッドタイプで測定距離を最短する機構がとられています。オシロスコープの波形はソフトウェア上で解析されデータ表示を行います。



QG Test Waveform



Qgs Time Measurement Waveform



MODEL

CWT2020Z/QGR520Z

SOFTWARE

TEST PLAN/SORT PLAN

1000/1000

BIN OUT

24

DC TEST

MEASURABLE DEVICES

MOS-FET, IGBT, DIODE

VOLTAGE/CURRENT

2000V/200A

TEST ITEMS

MOS-FET

Ids, Idg, Igsx, Igss, Isgs, BVds, BVdg, BVsg, Vfgd, Vfgs, Vfsds, Vfsdx+, Vfsdx-, Vp, Vth, Vth2, VdsON, RbsON, IdON, DHIDSS, GMP

IGBT

ICE, IGes, BVCE, ILGES+, ILGES-, VTHGB1, VTHGB2, VBLMK, VBLMK+, VBLMK-, VEmE, VEmE2, VEmER1, VEs1EC, VEmER2, VGEEm, IEmE1, IEs1EC, IEmE2, BVCEmX2+, BVCEmX2-, BVGESP, VGEI1, VGEEm2, ICG, ICG+, ICG-, ICEx+, ICEx-, LIGE, IGE, VEsE, ILCEEs, VCEsON, VCErON, VCEON, ICEON, IAE, IEmA, BVEG, IEsEm, IEmEs

DIODE

VF, LVf, VFCD, VRD, IRD, LIRD, Vfd, LVfd, ThDiVf, ThDiIz, ThDiVz, LThDiIz

QG TEST

MEASURABLE DEVICES(Nch Only)

MOS-FET, IGBT

TEST ITEM

Qgs, Qgd, Qg, Vth, Qgs time, Qgd time, Total Qg time

SETTING RANGE

VDD

20V~500V

Id(Limit)

1A~200A

IGF

0.1mA~100.0mA

VGF LIMIT

00.0V~30.0V

ON TIME

000 μs~999 μs

RL

Plug in

DIMENSIONS & WEIGHT

MAIN UNIT

1203(W)×1453(D)×2016(H)---780kg